



Product/Process Change Notice - PCN 25_0241 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887, USA

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. An acceptance or concern response should be submitted to ADI promptly. Any requests for samples of changed material or additional information must be made within 30 days of the notification. In accordance with JEDEC Standard 046, customers should acknowledge receipt of the PCN within 30 days of the PCN delivery. ADI contact information is listed below. Note: Revised fields are indicated by a red field name. See Appendix B for revision history.

Lack of acknowledgment of the PCN within 30 days constitutes acceptance of the change. After the acknowledgment, a lack of additional requests within 90 days constitutes acceptance of the change.

PCN Title:	AD4170-4 Die Revision
Publication Date:	19-Nov-2025
Effectivity Date:	21-Feb-2026 <i>(the earliest date that a customer could expect to receive changed material)</i>
Revision Description:	Initial Release.

Description Of Change:

Die revision to support:

1. Continuous SCLKs in Continuous Read. SCLK pulses are ignored when /CS and/or DRDY are de-asserted.
2. Main clock switching in standby mode.
3. Using single conversion mode with a continuous MCLK source.
4. Switching from standby mode to idle mode is now supported.
5. The Chip Grade register value has been updated from 0x03 to 0x04.

Reason For Change:

Implemented changes to enhance part performance and reliability.

Impact of the change (positive or negative) on fit, form, function & reliability:

No impact on fit, form, or function; this change enhances product performance and reliability.

Product Identification: *(this section will describe how to identify the changed material)*

The Chip Grade register value has been updated from 0x03 to 0x04. Changeover datecode is 2524.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results.

Supporting Documents:

Attachment 1: Type: Qualification Results Summary

ADI_PCN_25_0241_Rev_-_AD4170-4 Qualification_Results.pdf

Note: If applicable, the device material declaration will be updated due to material change.

ADI Contact Information:

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:	Europe:	Japan:	Korea:	Rest of Asia:
PCN_Americas@analog.com	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_Korea@analog.com	PCN_ROA@analog.com

Appendix A - Affected ADI Models:

Added Parts On This Revision - Product Family / Model Number (2)

AD4170-4 / AD4170-4BCPZ

AD4170-4 / AD4170-4BCPZ-RL7

Appendix B - Revision History:

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	19-Nov-2025	21-Feb-2026	Initial Release.